#### **Features**

- Fast Read Access Time 45 ns
- Low Power CMOS Operation
   100 μA max. Standby
   20 mA max. Active at 5 MHz
- JEDEC Standard Packages
   28-Lead 600-mil PDIP
   32-Lead PLCC
   28-Lead TSOP and SOIC
- 5V ± 10% Supply
- High Reliability CMOS Technology 2,000V ESD Protection 200 mA Latchup Immunity
- Rapid Programming Algorithm 100 µs/byte (typical)
- CMOS and TTL Compatible Inputs and Outputs
- Integrated Product Identification Code
- Commercial and Industrial Temperature Ranges

### **Description**

The AT27C512R is a low-power, high performance 524,288 bit one-time programmable read only memory (OTP EPROM) organized 64K by 8 bits. It requires only one 5V power supply in normal read mode operation. Any byte can be accessed in less than 45 ns, eliminating the need for speed reducing WAIT states on high performance microprocessor systems.

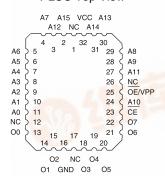
Atmel's scaled CMOS technology provides high speed, lower active power consumption, and significantly faster programming. Power consumption is typically only 8 mA in Active Mode and less than 10  $\mu$ A in Standby.

(continued)

## **Pin Configurations**

Pin Name	Function
A0 - A15	Addresses
O0 - O7	Outputs
CE	Chip Enable
OE /VPP	Output Enable/V <sub>PP</sub>
NC	No Connect

#### PLCC Top View



Note: PLCC Package Pins 1 and

PDIP, SOIC Top View

			$\neg$		1	
A15	d	1		28	Þ	VCC
A12	$\Box$	2		27	Þ	A14
A7	þ	3		26	Þ	A13
A6	þ	4		25	Þ	A8
A5	$\Box$	5		24	Þ	A9
A4	d	6		23	Þ	A11
АЗ	$\Box$	7		22	Þ	OE/VPF
A2	$\Box$	8		21	Þ	A10
A1	þ	9		20	Þ	CE
A0	$\Box$	10		19	Þ	O7
00	d	11		18	Þ	O6
01	þ	12		17	Þ	O5
02	þ	13		16	Þ	04
GND	þ	14		15	Þ	О3

### TSOP Top View

#### Type 1

DE/VPP =	00	22	21	00	Þ	CE	A10
A9 🛭	23	24	19	20	Ē		<b>O</b> 7
A13 🖳	25	26	17	18	Ĕ	06	O5
vcc T	27	28	15	16	Ĕ	04	О3
A12 A15	1	2	13	14	B	GND	02
A6 A7 🛱	3	4	11	12	B	01	00
A4 A5	5		9	10	k	A0	
A4 A3 =	7	6	9	8	Б	A2	A1

512K (64K x 8)
OTP
CMOS
EPROM

0015H





### **Description** (Continued)

The AT27C512R is available in a choice of industry standard JEDEC-approved one-time programmable (OTP) plastic PDIP, PLCC, SOIC, and TSOP packages. All devices feature two-line control (CE, OE) to give designers the flexibility to prevent bus contention.

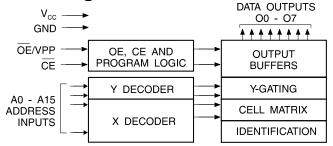
With 64K byte storage capability, the AT27C512R allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

Atmel's 27C512R has additional features to ensure high quality and efficient production use. The Rapid  $^{\!\top\!\!}$  Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 100  $\mu s/byte$ . The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages.

### **System Considerations**

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed data sheet limits, resulting in device non-conformance. At a minimum, a 0.1  $\mu F$  high frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the Vcc and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7  $\mu F$  bulk electrolytic capacitor should be utilized, again connected between the Vcc and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

### **Block Diagram**



## **Absolute Maximum Ratings\***

Temperature Under Bias55°C to +125°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground2.0V to +7.0V (1)
Voltage on A9 with Respect to Ground2.0V to +14.0V (1)
V <sub>PP</sub> Supply Voltage with Respect to Ground2.0V to +14.0V <sup>(1)</sup>

\*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1. Minimum voltage is -0.6V dc which may undershoot to -2.0V for pulses of less than 20 ns. Maximum output pin voltage is V<sub>CC</sub> + 0.75V dc which may overshoot to +7.0V for pulses of less than 20 ns.

## **Operating Modes**

Mode \ Pin	CE	OE/V <sub>PP</sub>	Ai	Outputs
Read	VIL	VIL	Ai	D <sub>OUT</sub>
Output Disable	VIL	V <sub>IH</sub>	X <sup>(1)</sup>	High Z
Standby	ViH	X <sup>(1)</sup>	Х	High Z
Rapid Program (2)	VIL	Vpp	Ai	DIN
PGM Inhibit	V <sub>IH</sub>	V <sub>PP</sub>	X <sup>(1)</sup>	High Z
Product Identification (4)	VIL	V <sub>IL</sub>	A9 = V <sub>H</sub> <sup>(3)</sup> A0 = V <sub>IH</sub> or V <sub>IL</sub> A1 - A15 = V <sub>IL</sub>	Identification Code

Notes: 1. X can be V<sub>IL</sub> or V<sub>IH</sub>.

2. Refer to Programming Characteristics.

3.  $V_H = 12.0 \pm 0.5 V$ .

4. Two identifier bytes may be selected. All Ai inputs are held low ( $V_{IL}$ ), except A9 which is set to  $V_H$  and A0 which is toggled low ( $V_{IL}$ ) to select the Manufacturer's Identification byte and high ( $V_{IH}$ ) to select the Device Code byte.





## **DC and AC Operating Conditions for Read Operation**

			AT27C512R								
		-45	-55	-70	-90	-12	-15				
Operating	Com.	0°C - 70°C									
Temp.(Case)	Ind.	-40°C - 85°C									
Vcc Supply		5V ± 10%									

## **DC and Operating Characteristics for Read Operation**

Symbol	Parameter	Condition	Min	Max	Units
ILI	Input Load Current	$V_{IN} = 0V$ to $V_{CC}$		±1	μΑ
ILO	Output Leakage Current	$V_{OUT} = 0V$ to $V_{CC}$		±5	μΑ
lon	V <sub>CC</sub> <sup>(1)</sup> Standby Current	$I_{SB1}$ (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		100	μΑ
IsB	VCC > Standby Current	$I_{SB2}$ (TTL), $\overline{CE}$ = 2.0 to $V_{CC}$ + 0.5V		1	mA
Icc	V <sub>CC</sub> Active Current	$\frac{f = 5 \text{ MHz}, I_{OUT} = 0 \text{ mA},}{CE} = V_{IL}$		20	mA
VIL	Input Low Voltage		-0.6	0.8	V
VIH	Input High Voltage		2.0	Vcc + 0.5	V
VoL	Output Low Voltage	I <sub>OL</sub> = 2.1 mA		0.4	V
VoH	Output High Voltage	I <sub>OH</sub> = -400 μA	2.4		V

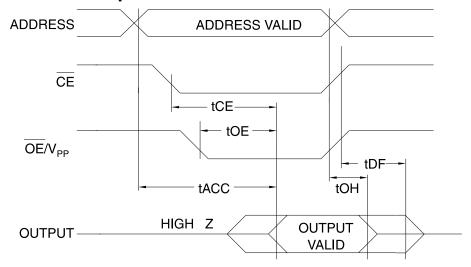
Note: 1.  $V_{CC}$  must be applied simultaneously or before  $\overline{OE}/V_{PP}$ , and removed simultaneously or after  $\overline{OE}/V_{PP}$ .

## **AC Characteristics for Read Operation**

				AT27C512R											
			-4	45	-{	55	-7	70	-(	90		12	-1	5	
Symbol	Parameter	Condition	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Units
t <sub>ACC</sub> (3)	Address to Output Delay	$\overline{CE} = \overline{OE}/V_{PP}$ = $V_{IL}$		45		55		70		90		120		150	ns
t <sub>CE</sub> (2)	CE to Output Delay	$\overline{OE}/V_{PP} = V_{IL}$		45		55		70		90		120		150	ns
toe (2, 3)	OE/V <sub>PP</sub> to Output Delay	CE = V <sub>IL</sub>		20		25		30		35		35		40	ns
t <sub>DF</sub> (4, 5)	OE/V <sub>PP</sub> or CE High Output Float, which	to ever occurred first		20		20		25		25		30		35	ns
toH	Output Hold from Address, CE or OE/ whichever occurred		7		7		7		0		0		0		ns

Notes: 2, 3, 4, 5. - see AC Waveforms for Read Operation.

# **AC Waveforms for Read Operation** (1)

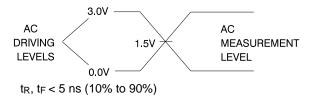


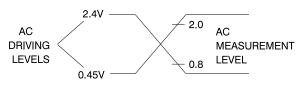
- Notes: 1. Timing measurement reference level is 1.5V for -45 and -55 devices. Input AC drive levels are  $V_{IL} = 0.0V$  and  $V_{IH} = 3.0V$ . Timing measurement reference levels for all other speed grades are  $V_{OL} = 0.8V$  and  $V_{OH} = 2.0V$ . Input AC drive levels are  $V_{IL} = 0.45V$  and  $V_{IH} = 2.4V$ .
  - 2. OE/V<sub>PP</sub> may be delayed up to t<sub>CE</sub> t<sub>OE</sub> after the falling edge of CE without impact on t<sub>CE</sub>.
- 3.  $\overline{\text{OE}/\text{V}_{PP}}$  may be delayed up to t<sub>ACC</sub> t<sub>OE</sub> after the address is valid without impact on t<sub>ACC</sub>.
- 4. This parameter is only sampled and is not 100% tested.
- Output float is defined as the point when data is no longer driven.

## **Input Test Waveforms and Measurement Levels**

For -45 and -55 devices only:

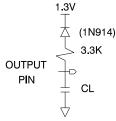
For -70, -90, -12, -15, and -20 devices:





t<sub>R</sub>, t<sub>F</sub> < 20 ns (10% to 90%)

## **Output Test Load**



Note: CL = 100 pF including jig capacitance, except for the -45 and -55 devices, where CL = 30 pF.

## **Pin Capacitance** (f = 1 MHz T = $25^{\circ}$ C)

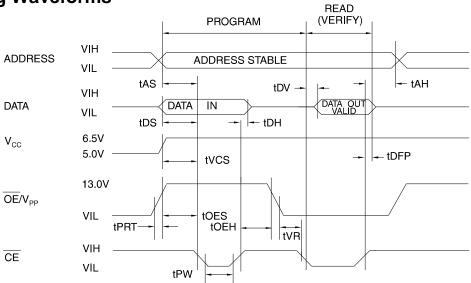
	Тур	Max	Units	Conditions
CIN	4	6	pF	$V_{IN} = 0V$
Соит	8	12	pF	Vout = 0V

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.





**Programming Waveforms** 



Notes: 1. The Input Timing Reference is 0.8V for  $V_{IL}$  and 2.0V for  $V_{IH}$ .

2. toe and tdepp are characteristics of the device but must be accommodated by the programmer.

## **DC Programming Characteristics**

 $T_{\text{A}}$  = 25  $\pm\,$  5°C,  $V_{\text{CC}}$  = 6.5  $\pm\,$  0.25V,  $\overline{\text{OE}}/V_{\text{PP}}$  = 13.0  $\pm\,$  0.25V

		Test	Li	mits	
Symbol	Parameter	Conditions	Min	Max	Units
ILI	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		±10	μА
VIL	Input Low Level		-0.6	0.8	V
V <sub>IH</sub>	Input High Level		2.0	V <sub>CC</sub> + 1	V
VoL	Output Low Voltage	$I_{OL} = 2.1 \text{ mA}$		0.4	V
Vон	Output High Voltage	$I_{OH} = -400 \mu A$	2.4		V
ICC2	V <sub>CC</sub> Supply Current (Program and Verify)			25	mA
I <sub>PP2</sub>	OE/V <sub>PP</sub> Current	$\overline{CE} = V_{IL}$		25	mA
VID	A9 Product Identification Voltage		11.5	12.5	V

## **AC Programming Characteristics**

 $T_A = 25 \pm 5^{\circ}C$ ,  $V_{CC} = 6.5 \pm 0.25V$ ,  $\overline{OE}/V_{PP} = 13.0 \pm 0.25V$ 

Sym-	Test	Liı	mits	Units
bol	Parameter Condtions* (1)	Min	Max	
tas	Address Setup Time	2		μS
toes	OE/V <sub>PP</sub> Setup Time	2		μS
toeh	OE/V <sub>PP</sub> Hold Time	2		μS
t <sub>DS</sub>	Data Setup Time	2		μS
tah	Address Hold Time	0		μS
t <sub>DH</sub>	Data Hold Time	2		μS
t <sub>DFP</sub>	CE High to Output Float Delay (2)	0	130	ns
tvcs	V <sub>CC</sub> Setup Time	2		μS
tpw	CE Program Pulse Width (3)	95	105	μS
$t_{\text{DV}}$	Data Valid from CE (2)		1	μS
t∨R	OE/V <sub>PP</sub> Recovery Time	2		μS
t <sub>PRT</sub>	OE/V <sub>PP</sub> Pulse Rise Time During Programming	50		ns

#### \*AC Conditions of Test:

Input Rise and Fall Times (10% to 90%	%) 20 ns
Input Pulse Levels	0.45V to 2.4V
Input Timing Reference Level	0.8V to 2.0V
Output Timing Reference Level	0.8V to 2.0V

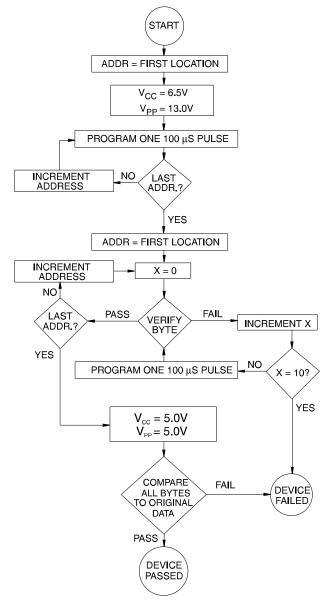
- Notes: 1. V<sub>CC</sub> must be applied simultaneously or before OE/V<sub>PP</sub> and removed simultaneously or after OE/V<sub>PP</sub>.
  - 2. This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven — see timing diagram.
  - 3. Program Pulse width tolerance is  $100 \, \mu sec \pm 5\%$ .

### Atmel's 27C512R Integrated **Product Identification Code**

		Pins					Hex			
Codes	A0	07	O6	O5	04	О3	O2	O1	00	Data
Manufacturer	0	0	0	0	1	1	1	1	0	1E
Device Type	1	0	0	0	0	1	1	0	1	0D

### **Rapid Programming Algorithm**

A 100 µs  $\overline{\text{CE}}$  pulse width is used to program. The address is set to the first location. VCC is raised to 6.5V and OE/V<sub>PP</sub> is raised to 13.0V. Each address is first programmed with one 100  $\mu$ s  $\overline{CE}$  pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive 100 µs pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked. OE/VPP is then lowered to V<sub>IL</sub> and V<sub>CC</sub> to 5.0V. All bytes are read again and compared with the original data to determine if the device passes or fails.





**Ordering Information** 

tACC	Icc	(mA)	Ondering Code	Dealers	Operation Range  Commercial (0°C to 70°C)	
(ns)	Active	Standby	Ordering Code	Package		
45	20	0.1	AT27C512R-45JC AT27C512R-45PC AT27C512R-45RC AT27C512R-45TC	32J 28P6 28R 28T		
	20	0.1	AT27C512R-45JI AT27C512R-45PI AT27C512R-45RI AT27C512R-45TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)	
55	20	0.1	AT27C512R-55JC AT27C512R-55PC AT27C512R-55RC AT27C512R-55TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)	
	20	0.1	AT27C512R-55JI AT27C512R-55PI AT27C512R-55RI AT27C512R-55TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)	
70	20	0.1	AT27C512R-70JC AT27C512R-70PC AT27C512R-70RC AT27C512R-70TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)	
	20	0.1	AT27C512R-70JI AT27C512R-70PI AT27C512R-70RI AT27C512R-70TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)	
90	20	0.1	AT27C512R-90JC AT27C512R-90PC AT27C512R-90RC AT27C512R-90TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)	
	20	0.1	AT27C512R-90JI AT27C512R-90PI AT27C512R-90RI AT27C512R-90TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)	
120	20	0.1	AT27C512R-12JC AT27C512R-12PC AT27C512R-12RC AT27C512R-12TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)	
	20	0.1	AT27C512R-12JI AT27C512R-12PI AT27C512R-12RI AT27C512R-12TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)	
150	20	0.1	AT27C512R-15JC AT27C512R-15PC AT27C512R-15RC AT27C512R-15TC	32J 28P6 28R 28T	Commercial (0°C to 70°C)	

(continued)

# **Ordering Information** (Continued)

tACC	•		Ordering Code	Doolsogo	Operation Denge	
(ns)	Active	Standby	Ordering Code	Package	Operation Range	
150	20	0.1	AT27C512R-15JI AT27C512R-15PI AT27C512R-15RI AT27C512R-15TI	32J 28P6 28R 28T	Industrial (-40°C to 85°C)	

Package Type					
32J	32 Lead, Plastic J-Leaded Chip Carrier (PLCC)				
28P6	28 Lead, 0.600" Wide, Plastic Dual Inline Package (PDIP)				
28R	28 Lead, 0.330" Wide, Plastic Gull Wing Small Outline (SOIC)				
28T	28 Lead, Thin Small Outline Package (TSOP)				

